

**Search Notes**

Application/Control No.

10/506,302

Examiner

Nguyen N. Hanh

Applicant(s)/Patent under  
Reexamination

ISHIHARA ET AL.

Art Unit

2834

**SEARCHED**

Class	Subclass	Date	Examiner
310	261	10/17/2006	HN
310	216	10/17/2006	HN
310	217	10/17/2006	HN
310	218	10/17/2006	HN
update search	All	4/7/07	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR